

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/045,036	TANAKA ET AL.	
	Examiner Tim Phan	Art Unit 3729	29/832

SEARCHED			
Class	Subclass	Date	Examiner
29	832	9/22/2003	TP
/	846	/	/
/	847	/	/
430	5	/	/
/	319	/	/
/	321	/	/
Updated	Search	12/8/2005	TP
All	Aboce	/	/
977	DIG.1	/	/

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
29	832	12/8/2005	TP
)	846		
)	847		
nano\$ with pigment with (photomask\$3 or mask\$3 or resist\$3..			